

IN THE  
UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s): Alison Chaiken, Gary Gibson

Confirmation N .:

Application No.:

Examiner:

Filing Date: 10/03/2003

Group Art Unit:

Title: Capping Layer for Enhanced Performance Phase-Change Media Device

Commissioner for Patents  
PO Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

This Information Disclosure Statement is submitted:

- ☒ under 37 CFR 1.97(b), or  
(Within three months of filing national application; or date of entry of national application; or before mailing date of first office action on the merits; whichever occurs last)
- ☐ under 37 CFR 1.97 (c) together with either a:  
☐ Statement under 37 CFR 1.97(e), or  
☐ a \$180.00 fee under 37 CFR 1.17(p), or  
(After the CFR 1.97 (b) time period, but before final action or notice of allowance, whichever occurs first)
- ☐ under 37 CFR 1.97 (d) together with a:  
☐ Statement under 37 CFR 1.97(e)(1) or (2), and  
☐ a \$180.00 fee set forth in 37 CFR 1.17(p).  
(Filed after final action, a notice of allowance, on or before payment of the issue fee)

Please charge to Deposit Account **08-2025** the sum of \$0.00 . At any time during the pendency of this application, please charge any fees required or credit any overpayment to Deposit Account **08-2025** pursuant to 37 CFR 1.25.

☒ Applicant(s) submit herewith Form PTO 1449 - Information Disclosure Statement together with any required copies of patents, publications or other information of which applicant(s) are aware, which applicant(s) believe(s) may be material to the examination of this application and for which there may be a duty to disclose in accordance with 37 CFR 1.56.

☐ A concise explanation of the relevance of foreign language patents, foreign language publications and other foreign language information listed on PTO Form 1449, as presently understood by the individuals(s) designated in 37 CFR 1.56 (c) most knowledgeable about the content is given on the attached sheet, or where a foreign language patent is cited in a search report or other action by a foreign patent office in a counterpart foreign application, an English language version of the search report or action which indicates the degree of relevance found by the foreign office is listed on form PTO 1449 and is enclosed herewith.

It is requested that the information disclosed herein be made of record in this application.

☒ I hereby certify that this correspondence is being deposited with the United States Postal Service as <sup>Express</sup> first class mail in an envelope addressed to:  
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☐ I hereby certify that this paper is being transmitted to the Patent and Trademark Office facsimile number \_\_\_\_\_ on \_\_\_\_\_  
Number of pages: \_\_\_\_\_

Typed Name: Steven W. Smyrski

Signature: 

Respectfully submitted,

Alison Chaiken, Gary Gibson

By 

Steven W. Smyrski

Attorney/Agent for Applicant(s)  
Reg. No. **38,312**

Date: **10/03/2003**

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**PATENT APPLICATION**

Sheet 1 of 1

<b>FORM PTO-1449</b>  <b>LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT</b>  (Use several sheets if necessary)	<b>ATTY. DOCKET NO.</b> <b>200312573-1</b>	<b>APPLICATION NO.</b>	<b>CONFIRMATION NO.</b>
	<b>APPLICANT</b> <b>Alis n Chaiken et al.</b>		
	<b>FILING DATE</b> <b>10/03/2003</b>	<b>GROUP</b>	

**REFERENCE DESIGNATION****U.S. PATENT DOCUMENTS**

EXAMINER INITIAL		DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
	1A	5,557,596	09/17/1996	Gibson	
	1B				
	1C				
	1D				
	1E				
	1F				
	1G				
	1H				
	1I				
	1J				
	1K				

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	Pages/Columns/Lines Where Relevant Passages/Figures Appear	Check if Translation attached
	1L					
	1M					
	1N					
	1O					
	1P					

**OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)**

	1Q	"Electronic properties of van der Waals-epitaxy films and interfaces" W. Jaegermann et al., published in "Electron Spectroscopies Applied to Low-Dimensional Materials," edited by H.P. Hughes and H.I. Starnberg, Kluwer Academic Publishers, Dordrecht, 2000
	1R	
	1S	

EXAMINER

DATE CONSIDERED